[TS14T4]

Nanometric Metrology and Computation 3

Date & Time	July 4(Thu.), 2024 / 14:00-15:30
Place	Room 209B
Session Chair(s)	Yooun Heo (Inha Univ.)

TS14T4_I_1 *Invited

14:00-14:30

Emergent Piezoelectric Effect at Engineered Polar Interfaces

Ming-Min Yang

(Hefei National Laboratory)

TS14T4_O_2 14:30-14:45

Moiré Charge Localization in Twisted Freestanding Oxide Membranes

Min-Su Kim¹, Kyoungjun Lee², Kyung Song³, Teruyasu Mizoguchi⁴, Ryo Ishikawa⁴, Ki-Tae Eom², Mark S. Rzchowski², Chang-Beom Eom², and Si-Young Choi^{1,5}

(1POSTECH, 2University of Wisconsin-Madison, 3KIMS, 4University of Tokyo, 5IBS)

TS14T4_I_3 *Invited 14:45-15:15

Interface Analysis of Nano-Scale Semiconductor Thin Films using Cross-sectional TEM Hu Young Jeong (UNIST)

TS14T4_O_4 15:15-15:30

Direct Probing of Chalcogen–Driven Atomic–Reconstruction in Thermodynamic Moiré Heterobilayer Dong–Hwan Yang^{1,2}, Kyo–Won Lee^{1,2}, Chang–Soo Lee¹, Moon–Ho Jo^{1,2}, and Si–Young Choi^{1,2} (*1POSTECH, *2IBS*)